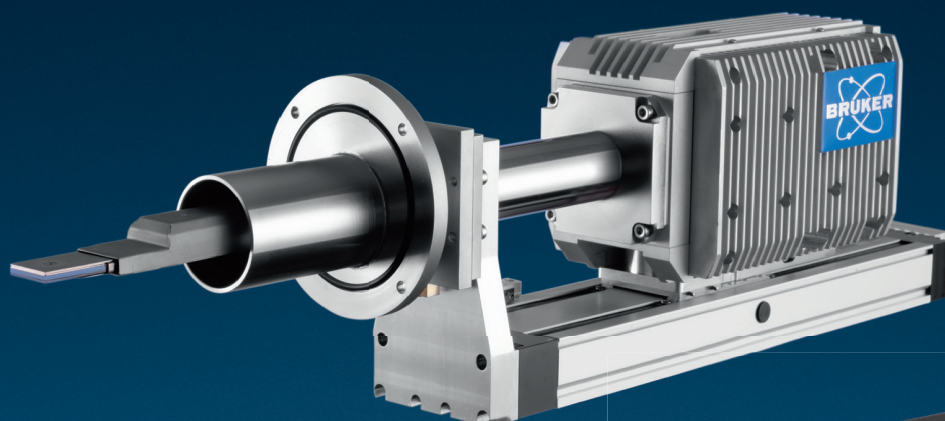


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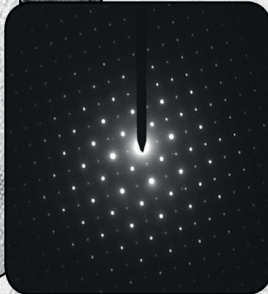
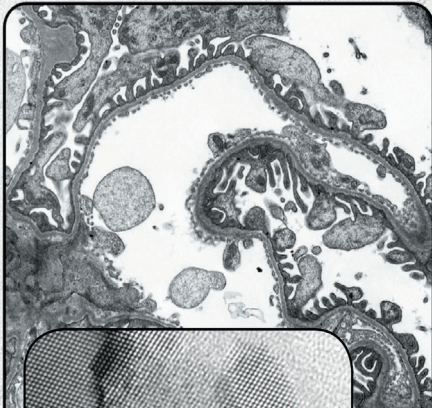
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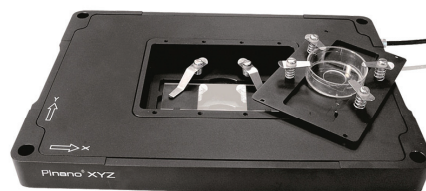


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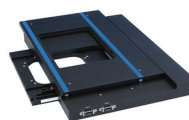
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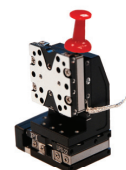
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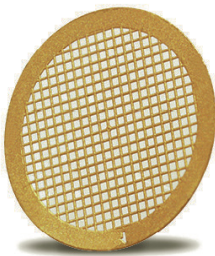
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The C-flat™ Advantage



C-flat™ leads to better data sets.

Made with patented technology, C-flat™ provides an ultra-flat surface that results in better particle dispersion and more uniform ice thickness. Patterning is done using deep-UV projection lithography, ensuring the most accurate and consistent hole shapes and sizes down to submicron features. The precise methods by which C-flat™ is manufactured eliminate artifacts such as excess carbon and edges around holes.

C-flat™ is affordable

C-flat™ is available in 25, 50, and 100 packs at a per-grid price less than competing products.

Applications

C-flat holey carbon grids provide the ideal specimen support to achieve high resolution data in cryoTEM making C-flat the perfect choice for:

- Single particle analysis
- Cryo electron tomography
- Automated TEM analysis

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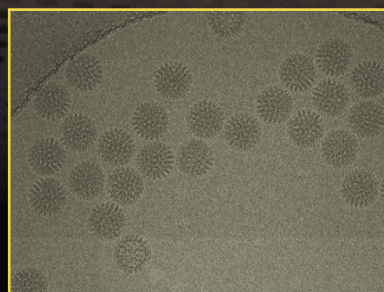
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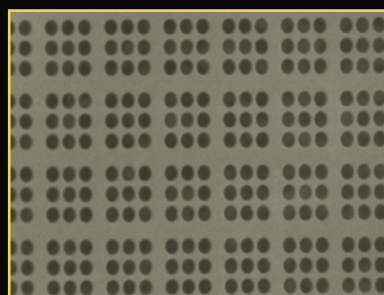
C-Flat™ is a clean, ultra-flat holey carbon film TEM grid primarily used for Cryo TEM and Automated TEM. With a variety of available hole diameters, mesh size, film thicknesses, and mesh material, there is a C-Flat™ product suitable for any application in the TEM.



Frozen-hydrated Bacteriophage Capsid
(data acquired on CF-1.2/1.4-4C).

Consistent

Researchers around the world have reported that the ultra-flat surface of C-flat™ leads to even ice thickness and uniform particle distribution, allowing for superior 3-D reconstructions. 2 µm hole sizes are standard, but various hole sizes are available to accommodate different particle sizes and magnifications.



Compatible

C-flat™ provides a regular array of analysis sites compatible with automated data collection software such as Legikon. This compatibility, in combination with the more uniform ice thickness and particle distribution reported by numerous researchers, results in more high-quality target sites per grid.



Clean

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